



IC-Gear Artefacts

The solution to determine the measurement uncertainty

 *pure
perfection*

FRENCO

General Information

Artefacts should be geometrically similar to the test pieces.
(= identity condition)



IC Artefacts

A new approach to gear artefacts or the solution to an old problem?

The design of conventional artefacts differs strongly from that of the actual test pieces. There is no similarity, let alone an identity condition.

IC artefacts can be constructed such that they have a similar gear profile to the test pieces. This is the precondition which is required to estimate the measurement uncertainty when measuring test pieces on gear inspection machines.

IC artefacts are feasible in all kinds of design. They can be made for running gears, external and internal gears with different modules and pitch circle diameters as well as for splines. Their geometric size can be matched to small plastic gears and HGV gears.



Artefacts should embody all important gear features



Combination of artefacts

Normal A

2 opposing tooth spaces R1 and R2 with a right hand helix angle based on $z = 32$

Two opposing tooth spaces L1 and L2 with a left hand helix angle based on $z = 33$

Certificate for:
 Profile
 Tooth trace
 Dimension over balls R1 . R2
 Dimension over balls L1 – L2

Normal B

Composite spur gearing

Certificate for:
 Profile
 Tooth trace
 Runout
 Single pitch
 Total pitch
 Dimension over balls

- Spur gears + Helical gears
- Sector gears + Composite gears
- Left flank + Right flank
- A tooth space + Opposite tooth space
- Even number of teeth + Odd number of teeth

Combinations of IC artefacts provide a comprehensive evaluation of accuracy deviations for the features illustrated on the right.

- Profile deviation:** Spur gears and helical gears with left and right hand helix angles
- Tooth trace deviation:** Spur gears and helical gears with left and right hand helix angles
- Pitch deviation:** Single pitch and total pitch
- Runout deviation:** Runout, axial position and roundness
- Dimension over two balls:** Odd and even number of teeth on straight and helical gearing

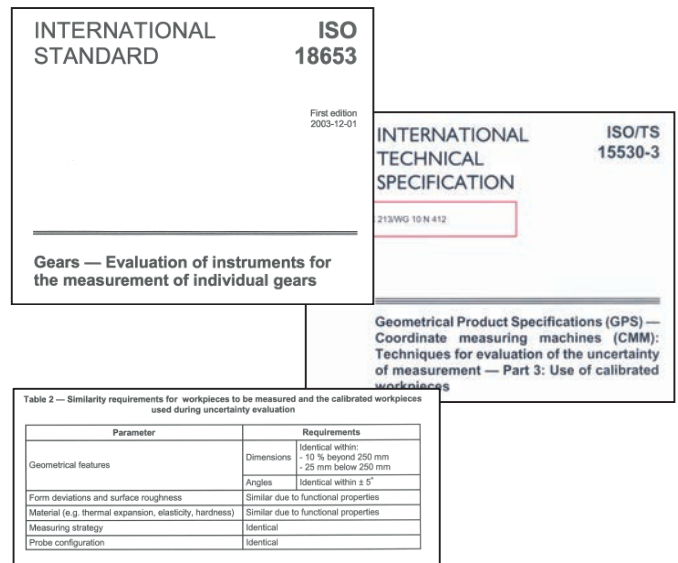
Determining the Measurement Uncertainty

Measurement uncertainty during gear measurements is mostly unknown in the industry. The theoretical calculation of the measurement uncertainty through budgets for industrial gear measurements has not yet been worked out.

ISO 18653 describes possible estimations of gear measurement uncertainty by means of workpiece-like artefacts. This procedure is applied on page 5 in this brochure.

Prerequisite of this method is the compliance of the identity condition between the artefacts and the workpieces to be inspected. The conditions are described in ISO/TS 15530-3.

The validity of the identity condition for gears and splines is not defined in the standards illustrated on the right. It could, however, be defined as follows:



Pitch circle ϕ in mm	from 10 to 40	from 40 to 80	from 80 to 120	from 120 to 180
Pitch circle ϕ	± 10	± 15	± 20	± 25
Number of teeth	± 40	± 30	± 25	± 20
Module	$\pm 0,5$	$\pm 1,0$	$\pm 1,5$	$\pm 2,0$
Pressure angle	$\pm 10^\circ$	$\pm 10^\circ$	$\pm 10^\circ$	$\pm 10^\circ$
Helix angle	$\pm 15^\circ$	$\pm 15^\circ$	$\pm 15^\circ$	$\pm 15^\circ$

The experimental estimation of the measurement uncertainty of gear measurements will be successful if these conditions are complied with:

- Geometrical similarity of artefacts and workpieces
- Material similarity of artefacts and workpieces
- Identical ambient conditions
- Identical measurement strategy
- Identical probe configuration

Limitation

The experimental estimation of the measurement uncertainty does not include influences of form deviations and surface roughness of the workpieces. The measurement uncertainty does therefore only apply to the precise position where the measurement was carried out and not to the gear as a whole.

In order for it to apply to the entire workpiece, the influences of form deviations and surface roughness must be determined separately and added to the measurement uncertainty.

Additional prerequisite

The artefacts to be used are calibrated with sufficient accuracy. The actual dimensions and actual form deviations and their measurement uncertainties are known. The exact positions on the artefact, where the actual values were determined, are also known. This data is given on the calibration certificate that is supplied with the IC artefact. DAkkS (Deutsche Akkreditierungsstelle GmbH - German Accreditation Body) calibration certificates are currently issued for IC artefacts A and B in line with the accredited parameters.

1. Determination of the standard uncertainty of a feature on the calibrated IC artefact u_c :

The artefact is measured under the same ambient conditions, with the same measurement strategy and probe configurations as the workpiece. All measurement values are documented. The measurement is repeated at least 10 times having regard to the normally occurring variations in temperature and other changes in the measurement conditions (e.g. clamping/unclamping).

$$u_c = \frac{U_c}{2}$$

U_c - Expanded measurement uncertainty of the calibration of the IC artefact

u_c - Standard uncertainty of the calibration of the IC artefact

2. Determination of the standard uncertainty u_p :

Determination of the arithmetic average of individual measurements

$$\bar{y} = \frac{y_1 + y_2 + \dots + y_n}{n}$$

y_i - Measurement results during the evaluation of uncertainties

\bar{y} - arithmetic average of all measurement results y_i

n - Number of individual measured values

The standard uncertainty u_p is then calculated with the known formula of the standard deviation:

$$u_p = \sqrt{\frac{1}{n-1} \cdot \sum_{i=1}^n (y_i - \bar{y})^2}$$

u_p - Standard uncertainty of the measurement process

3. Determination of the systematic deviation b :

To calculate the systematic deviation, the actual value of artefact x_c is compared to the arithmetic average of all measurement results y_i .

$$b = \bar{y} - x_c$$

b - Systematic deviation, identified during the evaluation of uncertainties

x_c - Calibrated value of a parameter of the IC artefact

4. Determination the measurement uncertainty U :

The estimated expanded measurement uncertainty, determined by this experimental method, therefore is:

Notes:

The influence of the workpiece is ignored.

The systematic deviation is integrated into the quadratic summation in the form of measurement uncertainty contribution (Source: F. Härtig, M.

Krystek; Correct treatment of systematic errors in the evaluation of measurement uncertainty; Proceedings of ISMTII-2009, Volume 1. St. Petersburg, p. 1-106 et sqq. Russia, 2009)

$$U = 2 \cdot \sqrt{u_c^2 + u_p^2 + b^2}$$

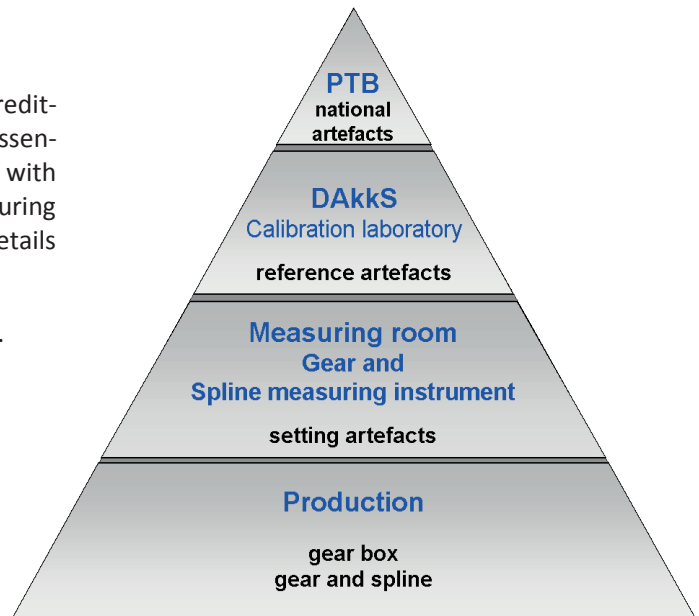
U - Expanded measurement uncertainty, determined experimentally

IC Artefacts with DAkKS Calibration Certificate

The calibration laboratory of FRENCO GmbH was accredited by DAkKS as conformity assessment body for all essential gear features (DK-15199-01-00), in accordance with DIN/ISO 17025. The accreditation is given for measuring zones, which are most commonly required. Further details on the scope of the accreditation can be viewed on

<http://www.dakks.de/as/ast/d/D-K-15199-01-00e.pdf>.

Artefacts outside the specified scope can be factory calibrated.



akkreditiert durch die / accredited by the				
Deutsche Akkreditierungsstelle GmbH				
als Kalibrierlaboratorium im / as calibration laboratory in the				
Deutschen Kalibrierdienst				
Kalibrierschein Calibration certificate	Kalibrierzeichen Calibration mark			
	<table border="1"> <tr><td>000143</td></tr> <tr><td>D-K-15199-01-00</td></tr> <tr><td>2011-06</td></tr> </table>	000143	D-K-15199-01-00	2011-06
000143				
D-K-15199-01-00				
2011-06				
Gegenstand Object	IC-Normal Bm für Profil, Flankenlinie, Teilung, Rundlauf und M_{sk}			
Hersteller Manufacturer	FRENCO GmbH Jakob-Baier-Straße 3 90518 Altdorf			
Typ Type	d = 105.000 mm; B = 0°			
Fabrikat/Serien-Nr. Serial number	53872 00 01 00			
Auftraggeber Customer	Muster GmbH Messstraße 1 D-04711 Scheinheim			
Auftragsnummer Order No.	20119999			
Anzahl der Seiten des Kalibrierscheines Number of pages of the certificate	7			
Datum der Kalibrierung Date of calibration	24.06.11			
Dieser Kalibrierschein dokumentiert die Rückführung auf nationale Normale zur Darstellung der Einheiten in Übereinstimmung mit dem Internationalen Einheitensystem (SI). Die DAkKS ist Unterzeichner der multilateralen Übereinkommen der European co-operation for Accreditation (EA) und der International Laboratory Accreditation Cooperation (ILAC) zur gegenseitigen Anerkennung der Kalibrierscheine. Für die Einhaltung einer angemessenen Frist zur Wiederholung der Kalibrierung ist der Benutzer verantwortlich.				
This calibration certificate documents the traceability to national standards, which realize the units of measurement according to the International System of Units (SI). The DAkKS is signatory to the multilateral agreements of the European co-operation for Accreditation (EA) and of the International Laboratory Accreditation Cooperation (ILAC) for the mutual recognition of calibration certificates. The user is obliged to have the object recalibrated at appropriate intervals.				
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This calibration certificate may not be reproduced other than in full except with the permission of both the Deutsche Akkreditierungsstelle GmbH and the issuing laboratory. Calibration certificates without signature are not valid.				
Datum Date	Leiter des Kalibrierlaboratoriums Head of the calibration laboratory			
	Bearbeiter Person in charge			
24.06.11	Dipl. Ing (FH) J. Kühl			
	J. Stellwag			
Frenco GmbH Verzahnungstechnik DAkKS Kalibrierlaboratorium für Verzahnungsmessgrößen Jakob-Baier-Str. 3 – 90518 Altdorf Tel. +49(0)9187 9522-0 – Fax. +49(0)9187 9522-40 Internet www.frenco.de – E-Mail info@frenco.de				

DAkKS (Deutsche Akkreditierungsstelle GmbH - German Accreditation Body) calibration certificates are currently issued for IC artefacts A and B as well as for conventional artefacts type 100, in line with the accredited parameters. DAkKS calibrated artefacts ensure the traceability to the SI unit "metre" and form part of the traceability chain to the national artefact.

The following parameters are calibrated, depending on the design:

- Profile deviation
- Tooth trace deviation
- Pitch deviation
- Runout deviation
- Dimension over two balls

The following details are described (explicitly and in form of an image) on the DAkkS calibration certificate:

- measurement conditions
- alignment planes for the determination of the reference axes
- measuring planes
- and the reference plane.

DAkkS calibration certificates are available in German and English.

1 Profil und Flankenlinie

1.1 Kalibrierverfahren

Das Verzahnungsnormal wurde auf einem Verzahnungsmessgerät kalibriert, dessen Abweichungen durch eine messaufgabenspezifische Kalibrierung mit PTB-kalibrierten Normalen ermittelt wurde, um die gemessenen Werte für F_a , f_{Hd} und F_b und f_{Hb} zu korrigieren.

1.2 Messbedingungen

Bei der Kalibrierung des Verzahnungsnormales wurden die Referenzachsen durch die Mittelpunkte zweier Kreise bestimmt. Die Kreismittelpunkte wurden aus je einer Rundlaufmessung berechnet, deren Messebenen sich auf den Mantelflächen der beiden Zylinder mit den Durchmessern 58.0 mm befanden. Die Messebenen der Rundlaufmessungen lagen nach oben 24.5 mm und nach unten 148.5 mm von der Messebene entfernt. (siehe auch Bild 1 / Ausrichthöhen P1)

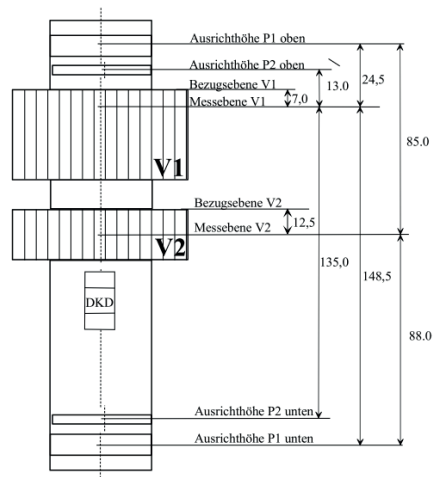


Bild 1: Lage der Bezugsebene und der Messebene (P= Prüfbund / V= Verzahnung)

Die Bezugsebene des Normalen ist die Stirnfläche der Verzahnung, auf der die Zähne beschriftet sind (siehe Bild 1). Durch die Prüfkurven wurden Regressionsgeraden nach der Methode der kleinsten Fehlerquadratsumme gelegt.

Verwendete Verzahnungsdaten und Auswertebereiche

Schrägungswinkel β [°]	Teilkreisdurchmesser d_b [mm]	Grundkreisdurchmesser d_g [mm]	Zahnfuß-Wälzlänge L_f [mm]	Zahnkopf-Wälzlänge L_s [mm]	Profil-Prüfbereich L_p [mm]	Flankenlinien-Prüfbereich L_s [mm]	Auswertebereich f_{ns} [mm]
0	84.000	80.112	9.2	18.2	9.0	28.0	28.0

1.4 Messergebnisse

In den nachfolgenden Tabellen sind die Messergebnisse aufgeführt. Es sind Mittelwerte aus mehreren Messungen.

Flankenlinie

Schrägungswinkel β [°]	Flanke Nr.	Flankenlinien-Gesamtabweichung F_b [µm]	Flankenlinien-Winkelabweichung f_{Hb} [µm]	Flankenlinien-Formabweichung f_{fb} [µm]
Verzahnung V1				
0	1R	1.3	R1.2	0.6
0	2L	1.2	R0.9	0.5

1.5 Messunsicherheit

In der nachfolgenden Tabelle sind die erweiterten Messunsicherheiten für die vorgenannten Messergebnisse aufgeführt.

Flankenlinie

Schrägungswinkel β [°]	Messunsicherheit U für F_b [µm]	Messunsicherheit U für f_{Hb} [µm]	Messunsicherheit U für f_{fb} [µm]
0	2.1	1.8	1.0

The gear data, calibration values and measurement uncertainties used for the calibration are presented in tabular form.

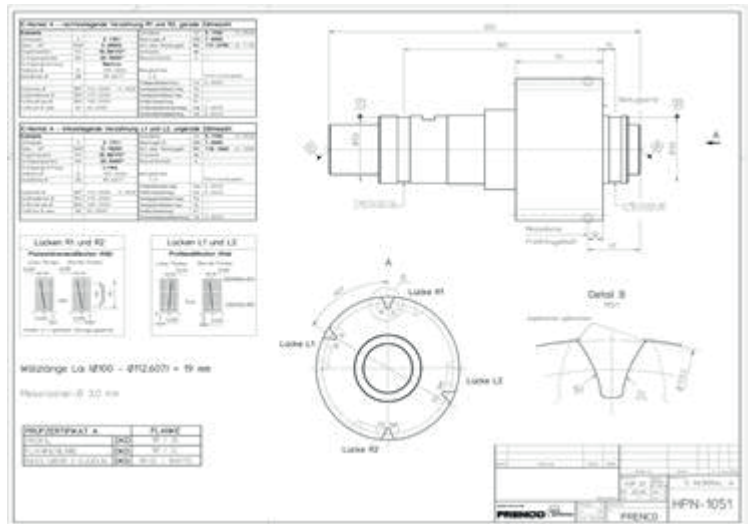
The inspection records / graphical representation of the measuring results are given in the appendix of the calibration certificate.

Artefact A

Example

Normal module: 3.5
 Base circle: 98.6677
 Pressure angle: 20°
 Helix angle: 20°R/20°L
 Number of teeth: 30/31

3 helix angles (in addition to 0°) are possible.



Artefact A and B can be customised to meet specific requirements:



...as gears, module 1.2

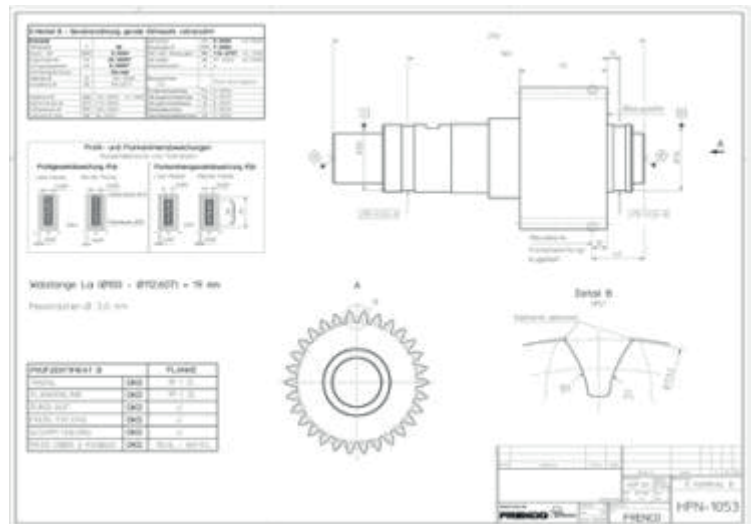


...as gears, module 2

Artefact B

Example

Module: 3.5
 Base circle: 98.6677
 Pressure angle: 20°
 Helix angle: 0°
 Number of teeth: 30



...as gears, module 3



...as splines, module 1.5

The combination artefact A/B can be customised to meet specific requirements:

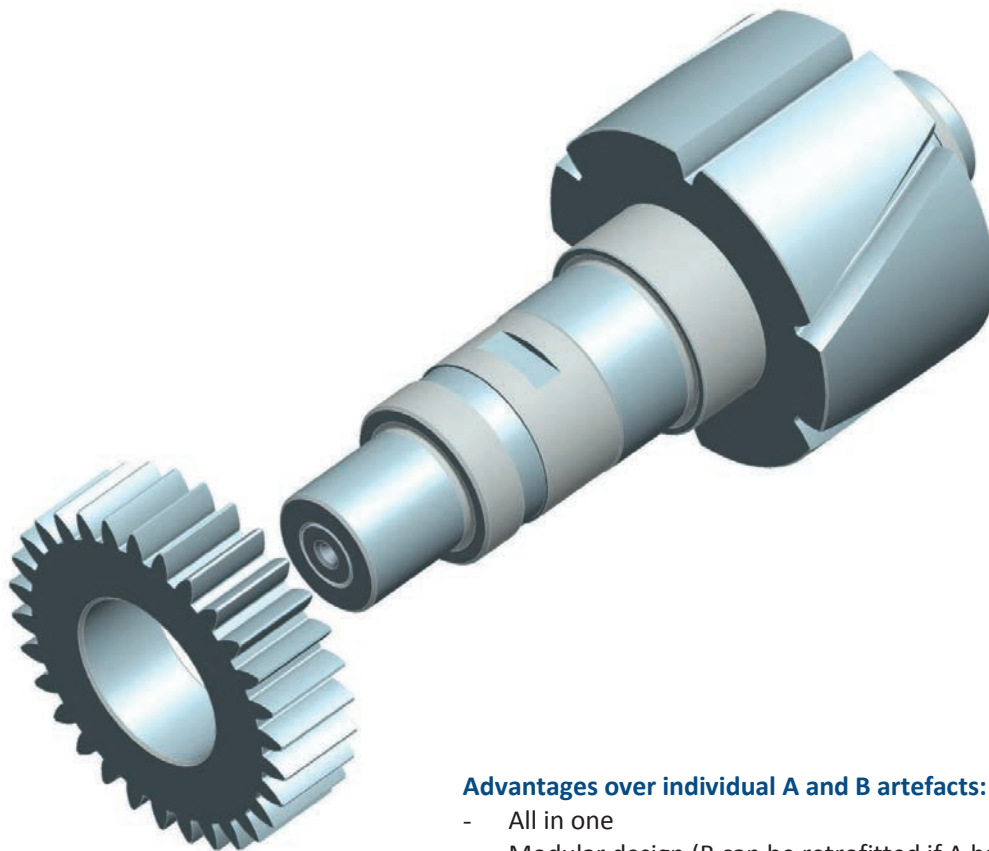
IC concept:

The combination artefact is, with regard to the gear data, adapted, as far as possible, to the customer base (Identical Conditions).

Artefact B can be furnished with defined pitch errors in order to test probe deflections.

Modular Design:

The basic body of an A artefact can be designed in such a way that artefact B can be retrofitted at a later date. This is an option for customers whose current focus is on the profile and tooth trace but may, in future, require a pitch artefact.



Advantages over individual A and B artefacts:

- All in one
- Modular design (B can be retrofitted if A has been prepared accordingly)
- Lower acquisition costs compared to two individual artefacts

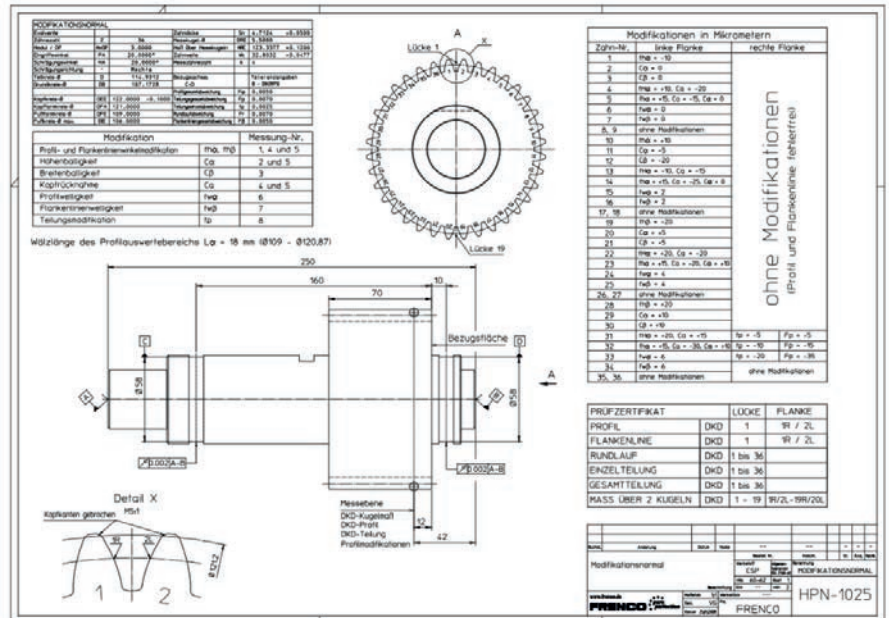
Disadvantages:

- Cannot be reground
- Higher weight

Modification Artefact M

2/80/17.5°

Modul: 2.25
Base circle: 90
Pressure angle: 17.5°



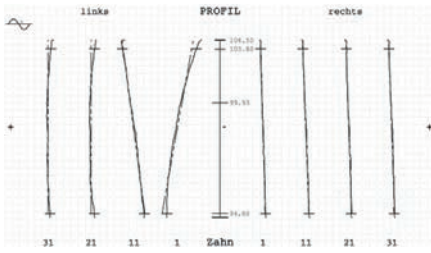
- How are modifications displayed at the measuring machine?
- How are relieves analysed?
- What does a pitch error look like?
- Which filters react how to waviness on the profile and the flank?
- How do measuring systems of different manufacturers react?

Questions that even we may not always know the answers to. The modification artefact (M) can help you in finding the answers. Different modifications such as crowning, relieves, angle errors, waviness and pitch errors have each been applied to one flank. Modification artefacts can be manufactured as described, or in accordance with your individual requirements. They are used for comparative measurements, long-term monitoring and for training purposes.



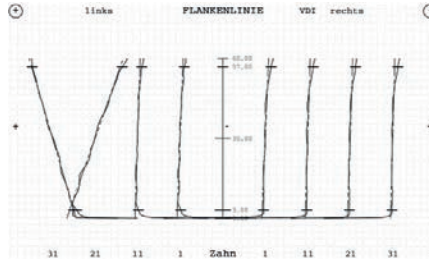
Measurement Results M

Messung 1	Modifikation	Zahn-Nr.	$fH\alpha$, μm
		1	-10
		11	+10

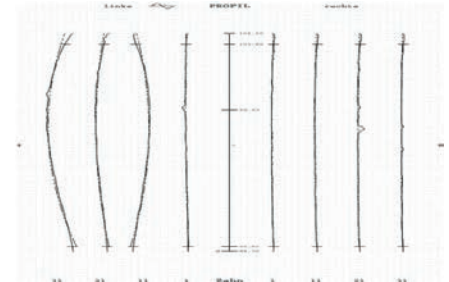


Messung 1	Modifikation	Zahn-Nr.	$fH\beta$, μm
		21	-20
		31	+20

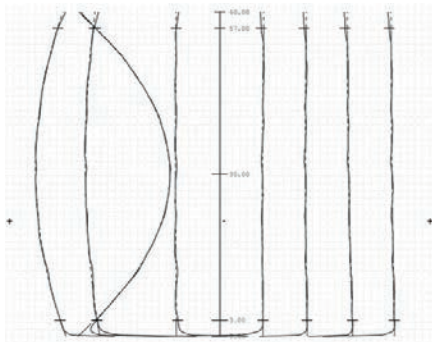
* Positiv (+) = größerer Schrägungswinkel



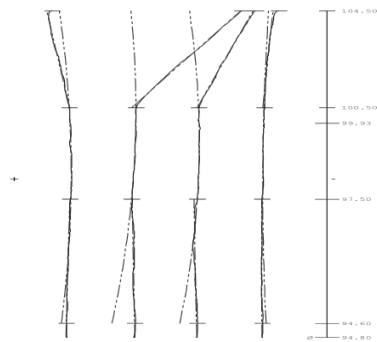
Messung 2	Modifikation	Zahn-Nr.	Ca , μm
		2	0
		12	-5
		22	+5
		32	+10



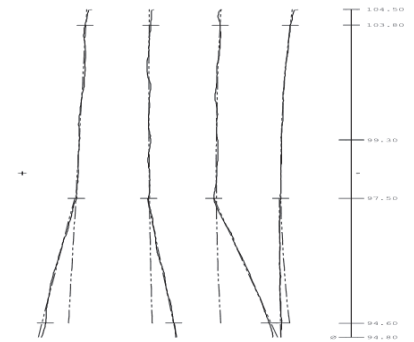
Messung 3	Modifikation	Zahn-Nr.	$C\beta$, μm
		3	0
		13	-35
		23	+5
		33	+10



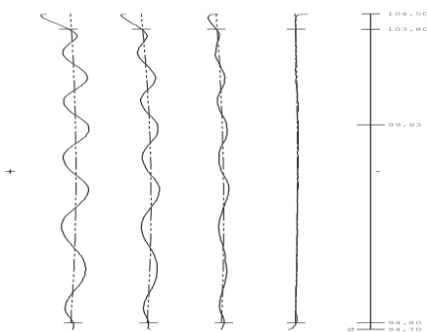
Messung 4	Modifikation	Zahn-Nr.	Ca , μm
		4	0
		14	-10
		24	-20
		34	+5



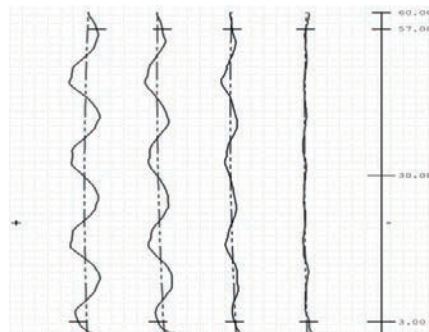
Messung 5	Modifikation	Zahn-Nr.	Cf , μm
		5	0
		15	-10
		25	-5
		35	+5



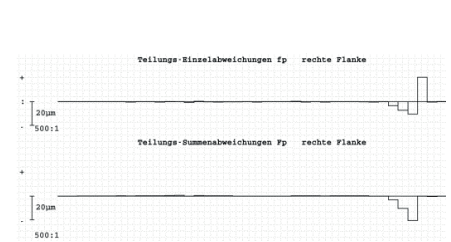
Messung 6	Modifikation	Zahn-Nr.	$fw\alpha$, μm
		6	0
		16	2
		26	4
		36	6



Messung 7	Modifikation	Zahn-Nr.	$fw\beta$, μm
		7	0
		17	2
		27	4
		37	6



Messung 8	Modifikation	Zahn-Nr.	fp , μm
		35	-5
		36	-10
		37	-20



Special Features

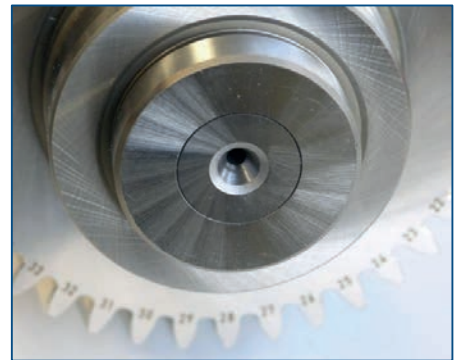
Protected inspection / aligning collars

- It is hence apparent where the reference axis will be generated
- High precision concentricity of approx. 1...2 μm ensures very high repeatability.



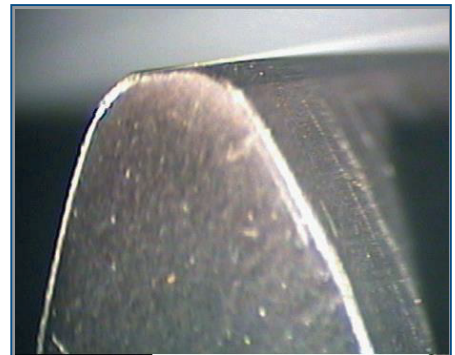
Carbide centres for long-term stability

- Frenco recommends single-end clamping in a chuck
- If the workpiece is clamped between centres, the carbide centres will ensure high repeatability



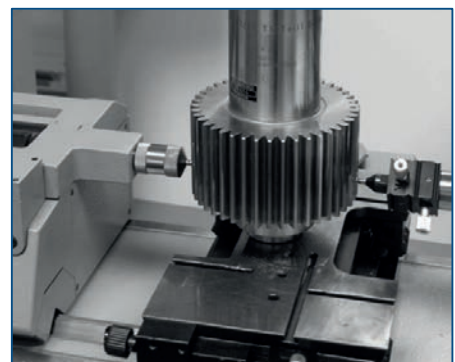
Chamfered tips

- Protecting the involutes in the tip area - to avoid having to recalibrate the artefact after each small knock.



Measured dimension over balls

- The dimensions over balls given in the inspection certificate are not the results of some calculations, but have actually been measured on the length measuring instrument.





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